## 600V 30A APT30DQ60K APT30DQ60KG\*

# **ULTRAFAST SOFT RECOVERY RECTIFIER DIODE**

## **PRODUCT APPLICATIONS**

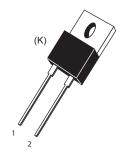
- Anti-Parallel Diode
   -Switchmode Power Supply
- -Inverters
  Free Wheeling Diode
  - -Motor Controllers
  - -Converters
  - -Inverters
- Snubber Diode
- PFC

## **PRODUCT FEATURES**

- Ultrafast Recovery Times
- · Soft Recovery Characteristics
- Popular TO-220 Package
- · Low Forward Voltage
- Low Leakage Current
- Avalanche Energy Rated

## **PRODUCT BENEFITS**

- Low Losses
- · Low Noise Switching
- Cooler Operation
- · Higher Reliability Systems
- Increased System Power Density





- 1 Cathode
- 2 Anode
  - Back of Case Cathode

#### **MAXIMUM RATINGS**

All Ratings:  $T_C = 25^{\circ}C$  unless otherwise specified.

Symbol	Characteristic / Test Conditions	APT30DQ60K(G)	UNIT	
V <sub>R</sub>	Maximum D.C. Reverse Voltage			
V <sub>RRM</sub>	Maximum Peak Repetitive Reverse Voltage	600	Volts	
V <sub>RWM</sub>	Maximum Working Peak Reverse Voltage			
I <sub>F(AV)</sub>	Maximum Average Forward Current ( $T_C = 117^{\circ}C$ , Duty Cycle = 0.5)	30		
I <sub>F(RMS)</sub>	RMS Forward Current (Square wave, 50% duty)	51	Amps	
I <sub>FSM</sub>	Non-Repetitive Forward Surge Current $(T_J = 45^{\circ}C, 8.3 \text{ms})$	320	1	
E <sub>AVL</sub>	Avalanche Energy (1A, 40mH)	20	mJ	
T <sub>J</sub> ,T <sub>STG</sub>	Operating and StorageTemperature Range	-55 to 175	- °C	
T <sub>L</sub>	Lead Temperature for 10 Sec.	300		

## STATIC ELECTRICAL CHARACTERISTICS

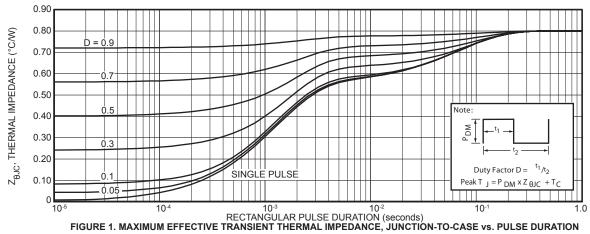
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Symbol	Characteristic / Test Conditions		MIN	TYP	MAX	UNIT	
V <sub>F</sub>	Forward Voltage	I <sub>F</sub> = 30A		2.0	2.4	Volts	
		I <sub>F</sub> = 60A		2.4			
		I <sub>F</sub> = 30A, T <sub>J</sub> = 125°C		1.7			
I <sub>RM</sub>	Maximum Reverse Leakage Current	V <sub>R</sub> = 600V			25		
		V <sub>R</sub> = 600V, T <sub>J</sub> = 125°C			500	μA	
C <sub>T</sub>	Junction Capacitance, V <sub>R</sub> = 200V			36		pF	

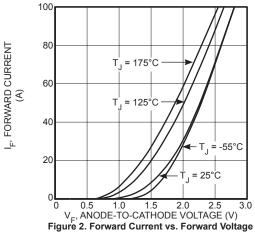
Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
t <sub>rr</sub>	Reverse Recovery Time $I_F = 1A$ , $di_F/dt = -100A/\mu s$ , $V_R = 30V$ , $T_J = 25$ °C		-	23		ns
t <sub>rr</sub>	Reverse Recovery Time	$I_F = 30A$ , $di_F/dt = -200A/\mu s$ $V_R = 400V$ , $T_C = 25^{\circ}C$	ı	30		115
Q <sub>rr</sub>	Reverse Recovery Charge		-	55		nC
I <sub>RRM</sub>	Maximum Reverse Recovery Current		-	3	-	Amps
t <sub>rr</sub>	Reverse Recovery Time	$I_F = 30A$ , $di_F/dt = -200A/\mu s$ $V_R = 400V$ , $T_C = 125$ °C	-	175		ns
Q <sub>rr</sub>	Reverse Recovery Charge		-	485		nC
I <sub>RRM</sub>	Maximum Reverse Recovery Current		-	6	-	Amps
t <sub>rr</sub>	Reverse Recovery Time	$I_F = 30A$ , $di_F/dt = -1000A/\mu s$ $V_R = 400V$ , $T_C = 125^{\circ}C$	-	75		ns
Q <sub>rr</sub>	Reverse Recovery Charge		-	855		nC
I <sub>RRM</sub>	Maximum Reverse Recovery Current		-	22		Amps

## THERMAL AND MECHANICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
R <sub>eJC</sub>	Junction-to-Case Thermal Resistance			.80	°C/W
W <sub>T</sub>	Package Weight		0.07		oz
			1.9		g
Torque	Maximum Mounting Torque			10	lb•in
				1.1	N•m

 ${\bf Microsemi\ reserves\ the\ right\ to\ change,\ without\ notice,\ the\ specifications\ and\ information\ contained\ herein.}$ 





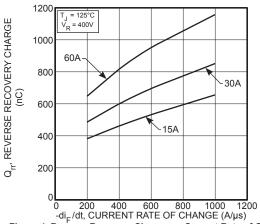
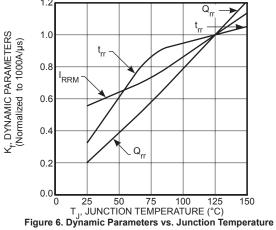
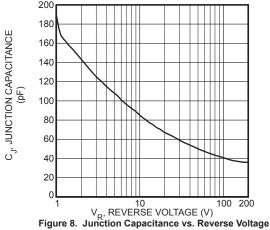


Figure 4. Reverse Recovery Charge vs. Current Rate of Change





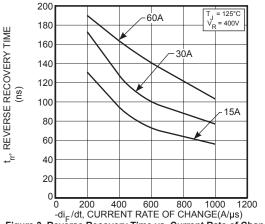


Figure 3. Reverse Recovery Time vs. Current Rate of Change

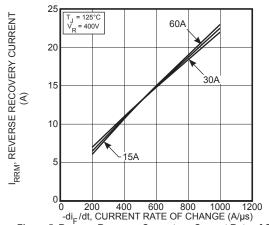


Figure 5. Reverse Recovery Current vs. Current Rate of Change

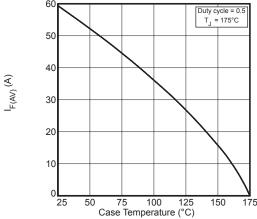


Figure 7. Maximum Average Forward Current vs. CaseTemperature

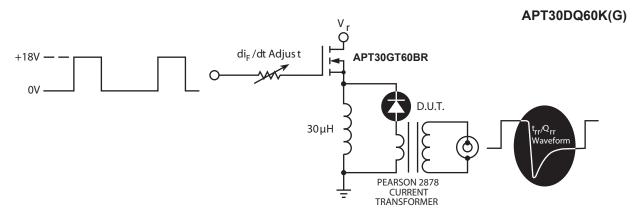


Figure 9. Diode Test Circuit

- I<sub>F</sub> Forward Conduction Current
- 2 di<sub>E</sub>/dt Rate of Diode Current Change Through Zero Crossing.
- 3 I<sub>RRM</sub> Maximum Reverse Recovery Current
- 4 t<sub>rr</sub> Reverse Recovery Time measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through I<sub>RRM</sub> and 0.25, I<sub>RRM</sub> passes through zero.
- $\mathbf{5}$   $\mathbf{Q}_{\mathrm{rr}}$  Area Under the Curve Defined by  $\mathbf{I}_{\mathrm{RRM}}$  and  $\mathbf{t}_{\mathrm{RR}}$

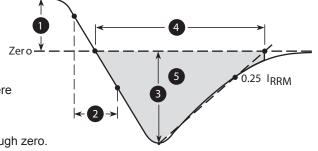
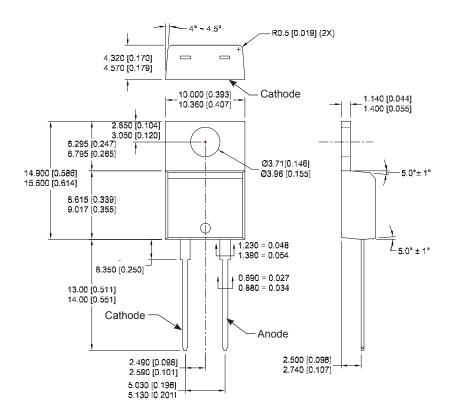


Figure 10. Diode Reverse Recovery Waveform Definition

## TO-220 (K) Package Outline e3 100% Sn



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